

Notice of References Cited			Application/Control No. 09/887,781	Applicant(s)/Patent Under Reexamination ANN ET AL.
			Examiner Tan Dean D. Nguyen	Art Unit 3689

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-2002/0069102	06-2002	Vellante et al.	705/10
*	C US-2002/0133368	09-2002	Strutt et al.	705/1
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K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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